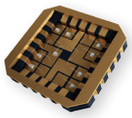
Meeting the New Space Electronics® Challenge

Select the optimum reliability screening level for each LEO system

The combination of TT Electronics' New Space Electronics® screening programme and space-proven die, with collaboration from Charcroft's engineering specialists, ensures cost-effective reliability for Low Earth Orbit (LEO) systems. TT Electronics is offering two new screening routes (NS1 and NS2) which are in line with both MIL and ESA standards. These will also help in reducing the overall flight cost of commercial LEO flights.

Select your package

- Standard ceramic small signal
- SMT power packages
- Ceramic diodes
- Traditional metal can
- Modern metals
- Low-cost packaging
- Fully customised Multi-Chip Arrays (MCA)



Select your semiconductor

- Small signal
- Small signal diodes
- JFETs
- Power diodes
- Power MOSFETs
- Schottky barrier

Select your screening options

- Stabilising bake
- Pre-cap inspection
- High-temperature reverse bias
- High-temperature gate bias
- Operational life
- Temperature cycling
- Acceleration
- Particle impact noise detection
- Hermetic seal testing
- Residual gas analysis
- Radiography
- Total Irradiated Dose (TID)
- Single Event Upset (SEU)
- Buy-off inspection
- Lot validation and group testing

Download the Brochure
www.charcroft.com/NewSpaceElectronics

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Charcroft: Challenge Accepted

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Passives, power, interconnect, emech and more